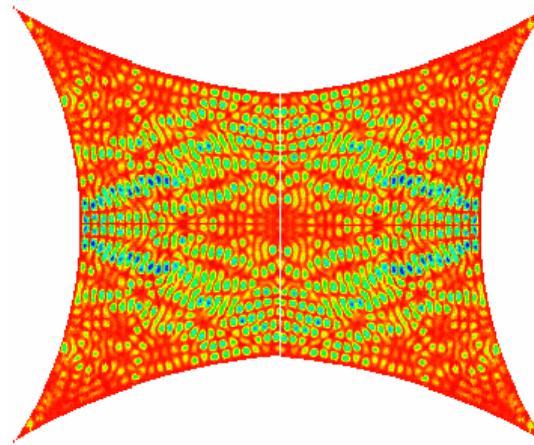




# Prediction and measurement of induced voltages inside complicated enclosures using wave-chaos

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Thomas M. Antonsen Jr., Edward Ott, Steven M. Anlage



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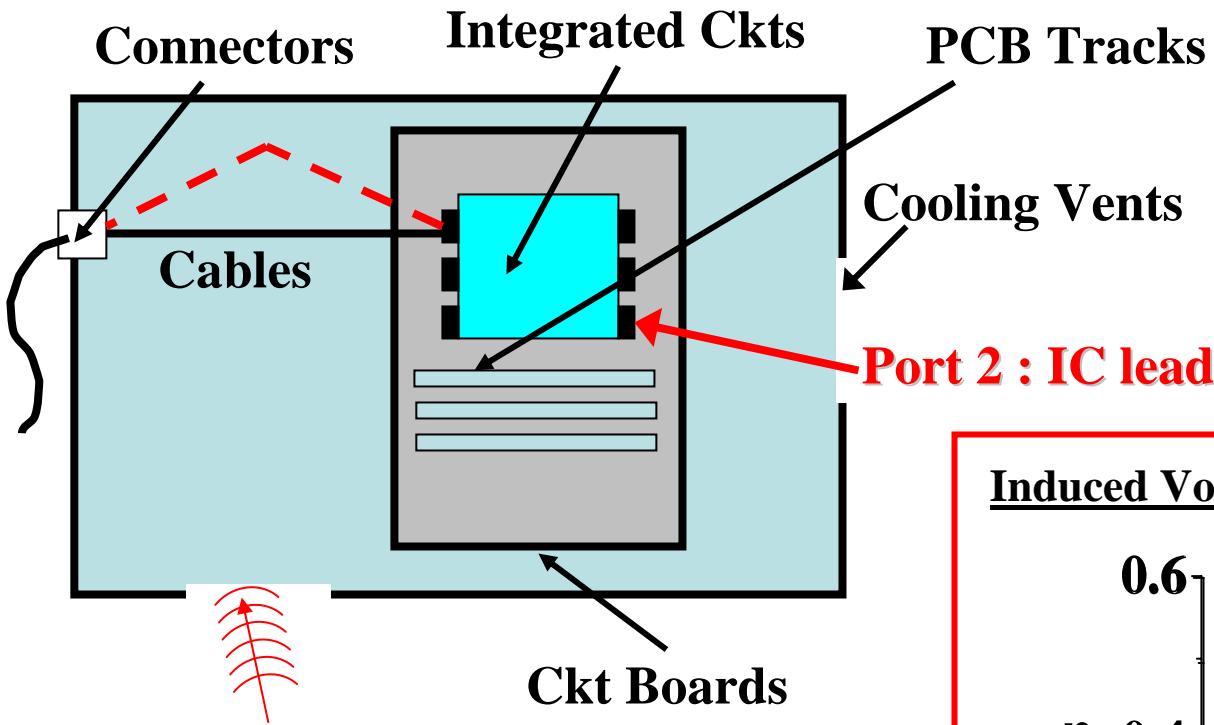
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## Motivation :- The “Four Famous” Questions:

- Is there some fast, simple and accurate way to predict the voltages induced at specific points within a complicated metallic enclosure (e.g. computer-box) due to external radiation?
- What factors determine the nature of these induced voltages ?
- Is there some “optimally shaped” wave-form for the external radiation, for which the electronics within the enclosure is most susceptible ?
- Is it possible to engineer an enclosure to make it resistant to HPM attack ?

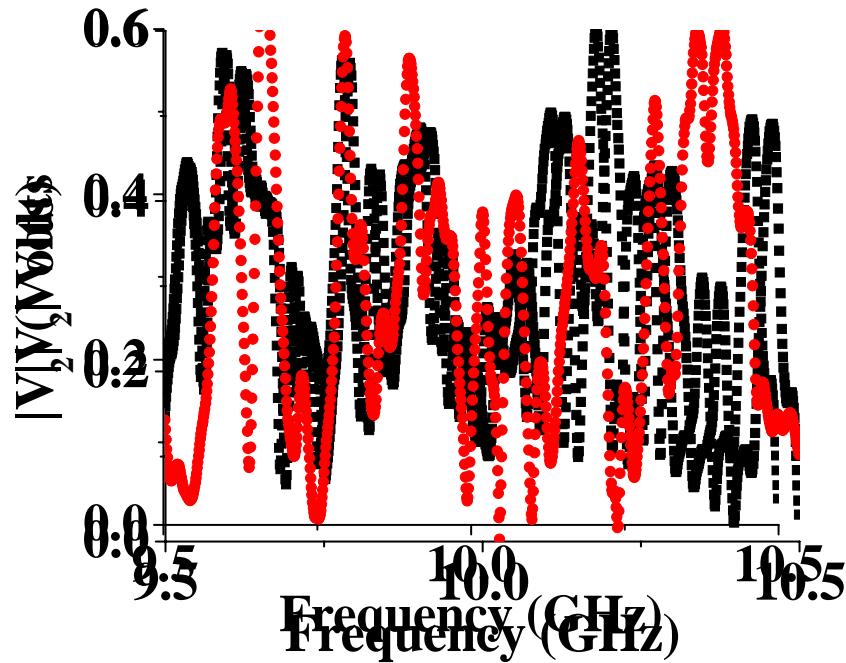
# 1. Can we predict the voltages induced at specific locations in a computer-box due to a external RF radiation?



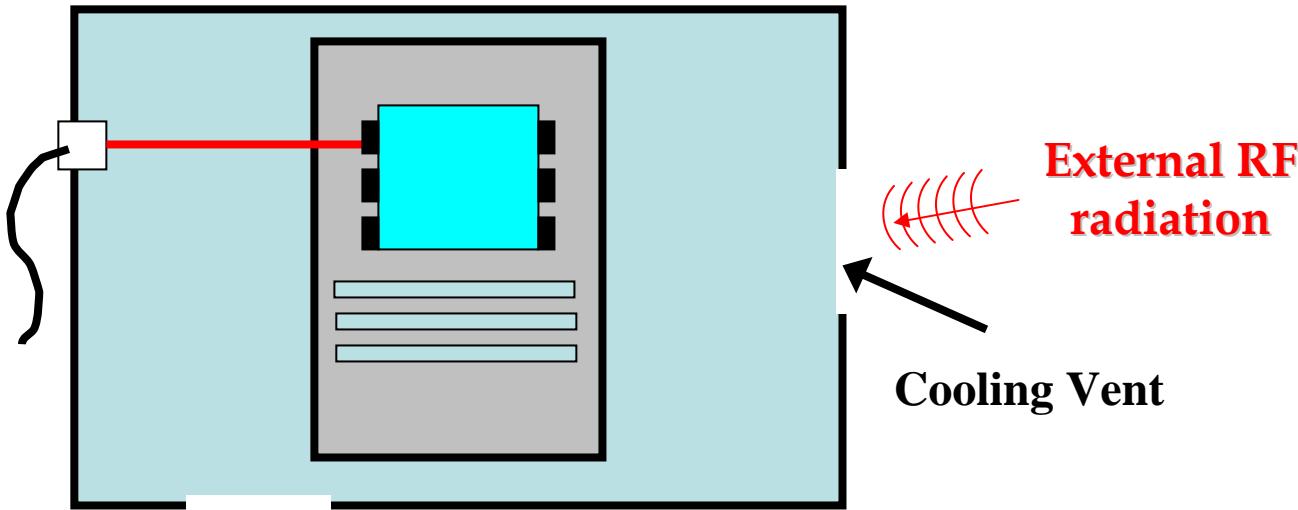
**Port 1: External RF  
radiation**

- Extreme sensitivity to system details makes numerical EM solutions based on Maxwell's equations impractical.
- Use Statistical Description !!

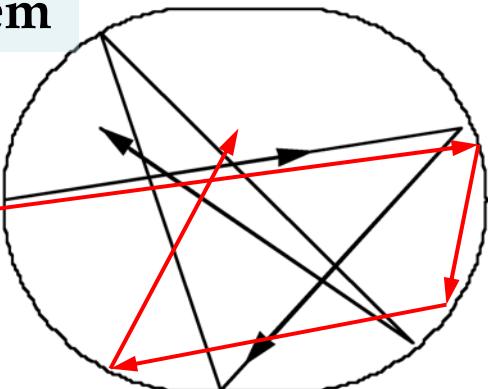
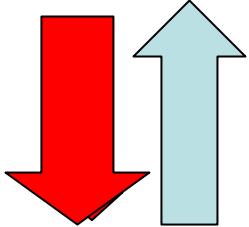
Induced Voltages at port 2 in a computer-box



## Our outlook to this problem:- Formulating the Random Coupling Model



Treat the  
computer-box  
as a wave-  
chaotic system



Chaotic Ray  
Trajectories

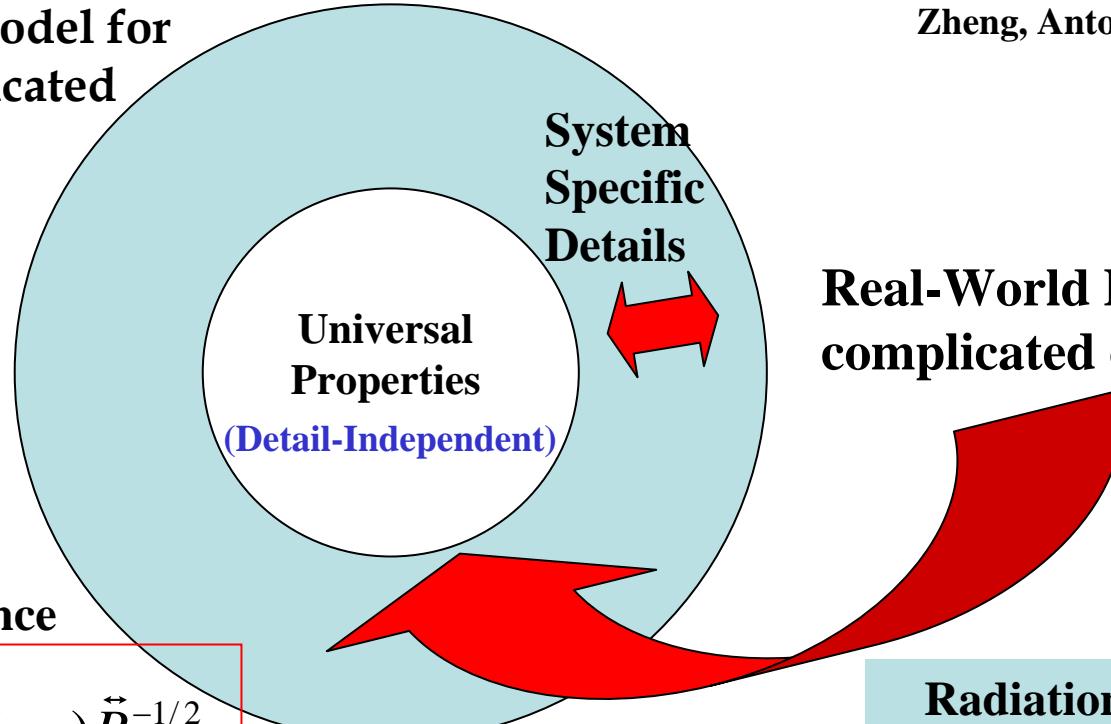
- Use Universal Properties of Wave Chaotic Systems to predict induced voltage distributions at specific locations inside the enclosure.

# Random Coupling Model (RCM)- “In a Nut Shell”

- RCM: Stochastic model for impedance of complicated enclosures

Electromagnetics, 26, 3 (2006).  
Electromagnetics, 26, 37 (2006).

Zheng, Antonsen, Ott

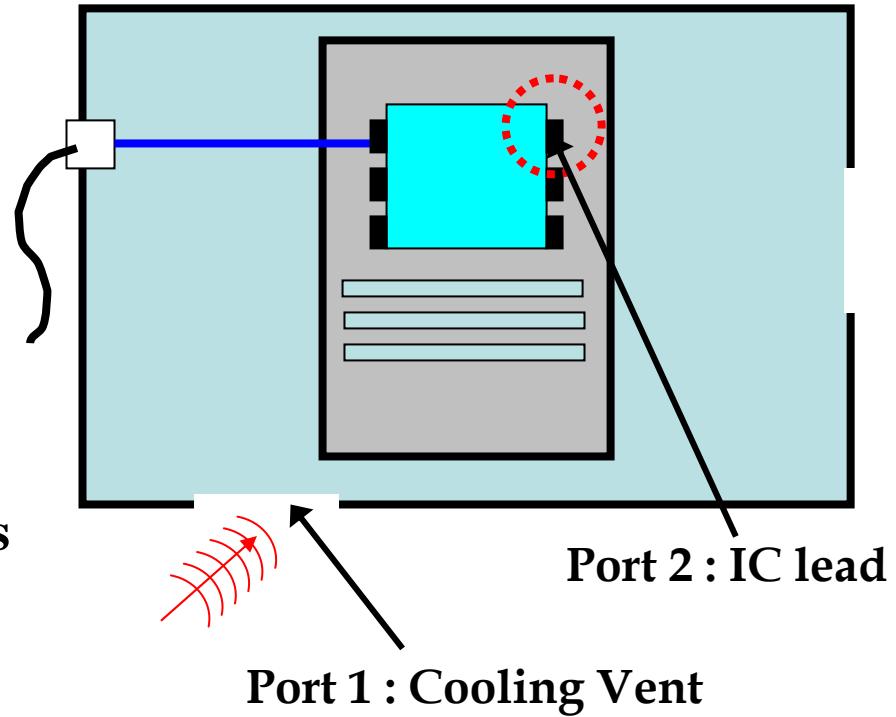
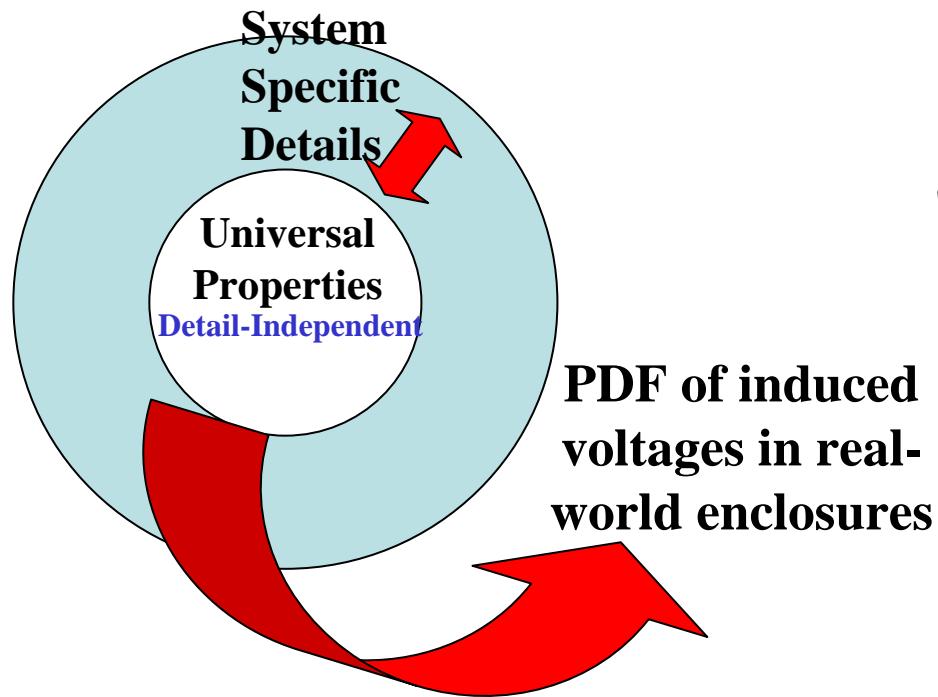


**Real-World Data on complicated enclosures**

- Statistical Description of normalized impedance depends only on a dimensionless “loss-parameter”

$$\alpha = \frac{k^2}{\Delta k_n^2 Q}$$

# Implications of RCM to Real-world 3D cavities



2. What minimum information do I need to predict the range of voltages on port 2 because of 'x' watts of power injected into port 1?

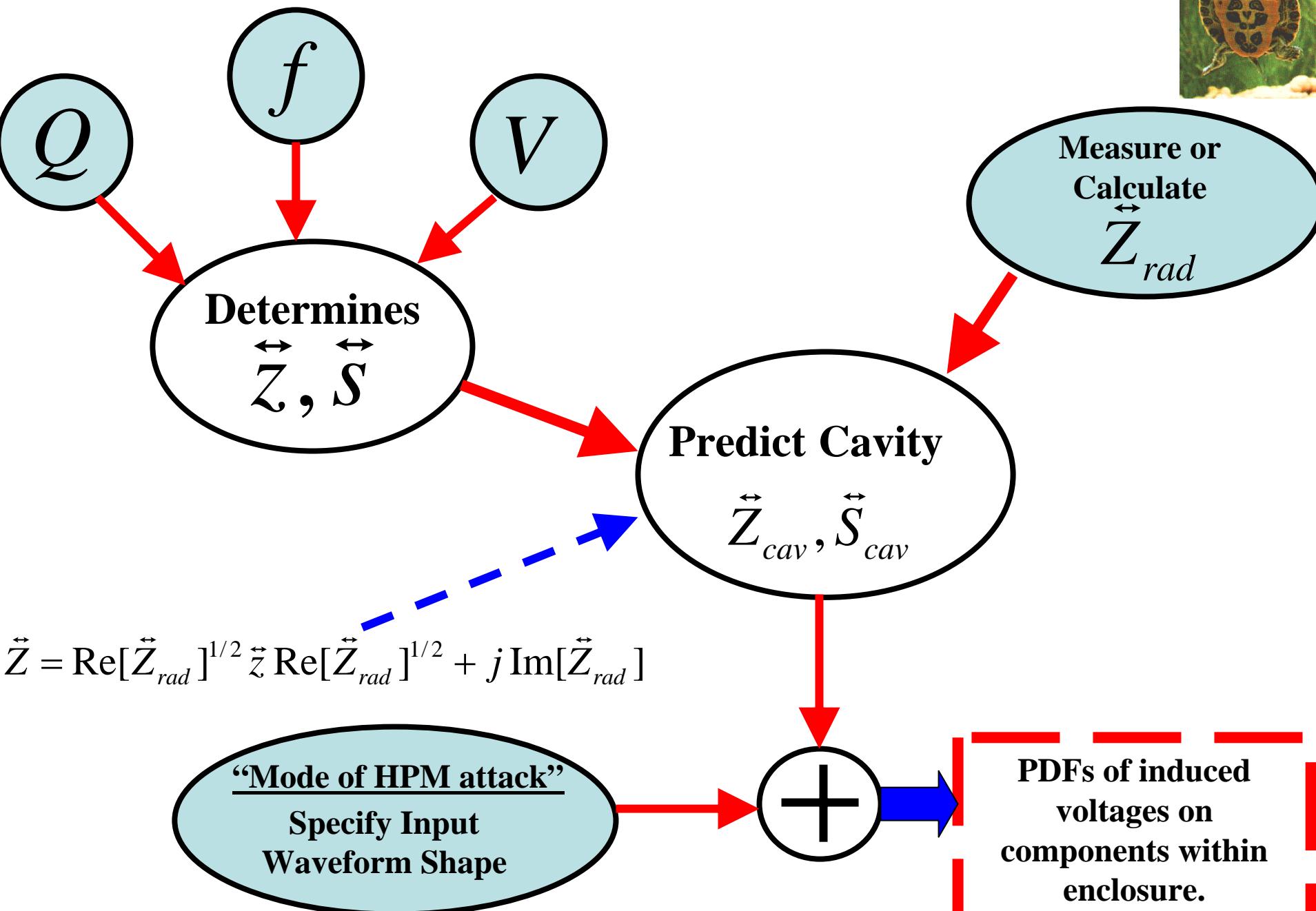
Minimum Information to predict PDF of induced voltages at port 2:

Frequency, Volume  
Losses }  $\alpha$

Radiation impedance of the ports  
Radiated power Wave-form from port 1

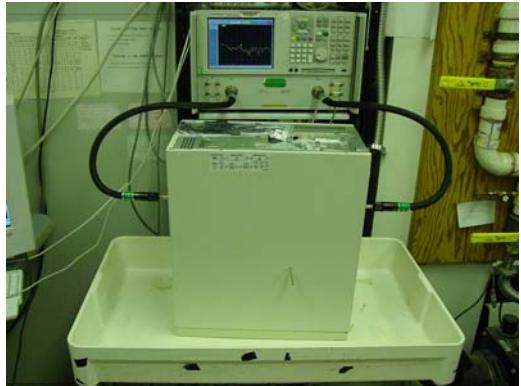
Determine the shape and scales of the induced voltage PDFs

# “Terrapin algorithm” for *a priori* prediction of Induced Voltage PDFs

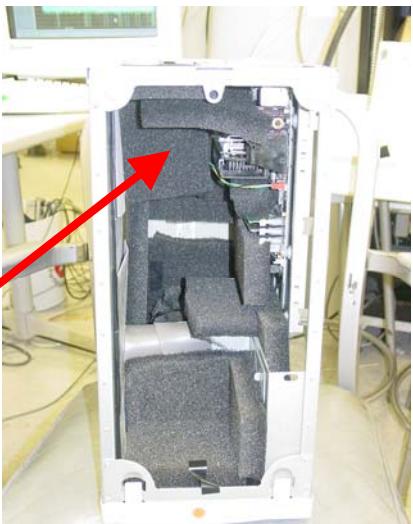


# “3D Real-World” Test of the Random Coupling Model and the “Terrapin Algorithm”

- Frequency Range: 2GHz to 20 GHz ( $\lambda \ll L$ )
- Ensemble Averaging over ~20 positions of the mode-stirrer.

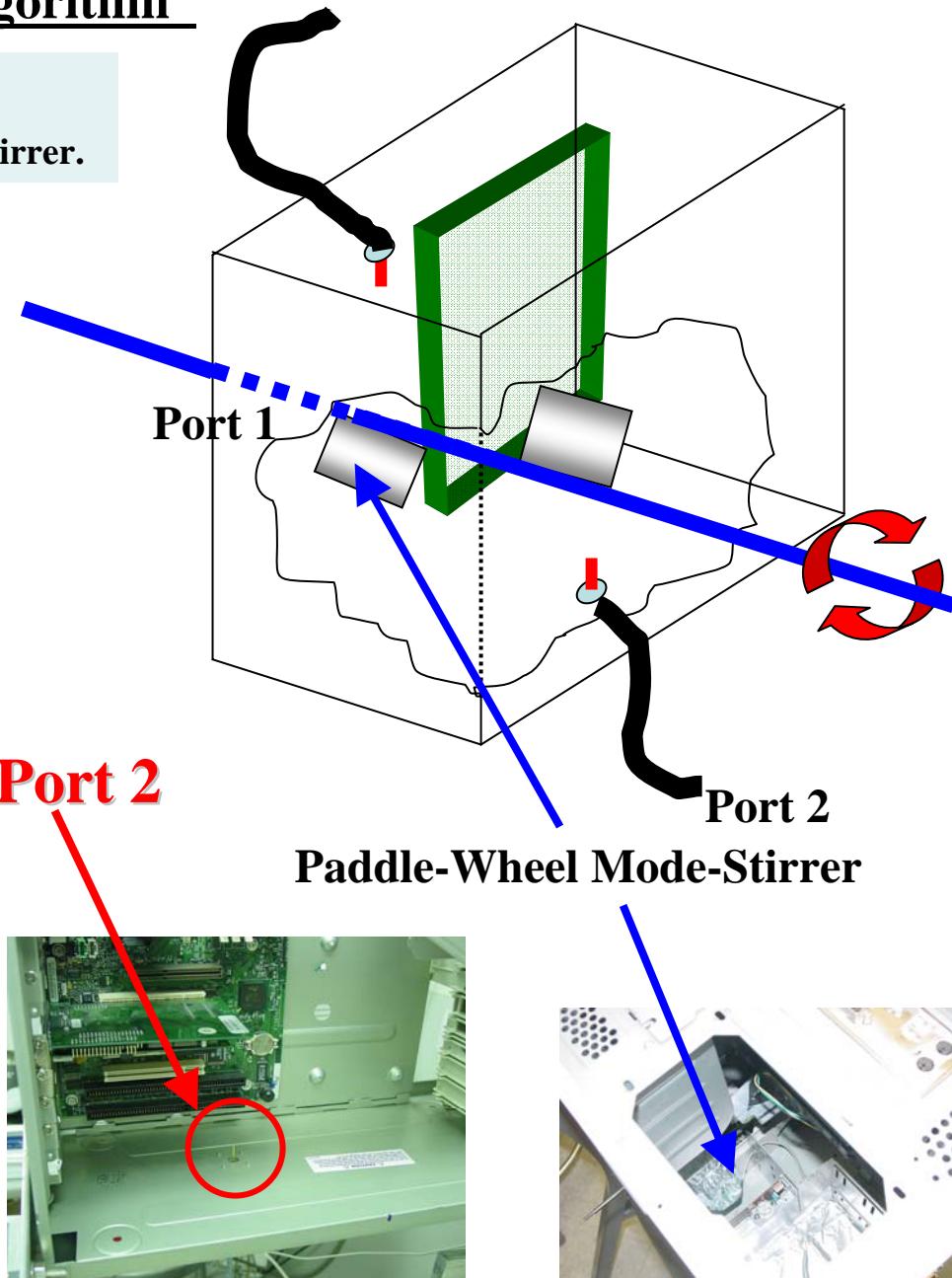


Experimental Setup [Cavity Case]

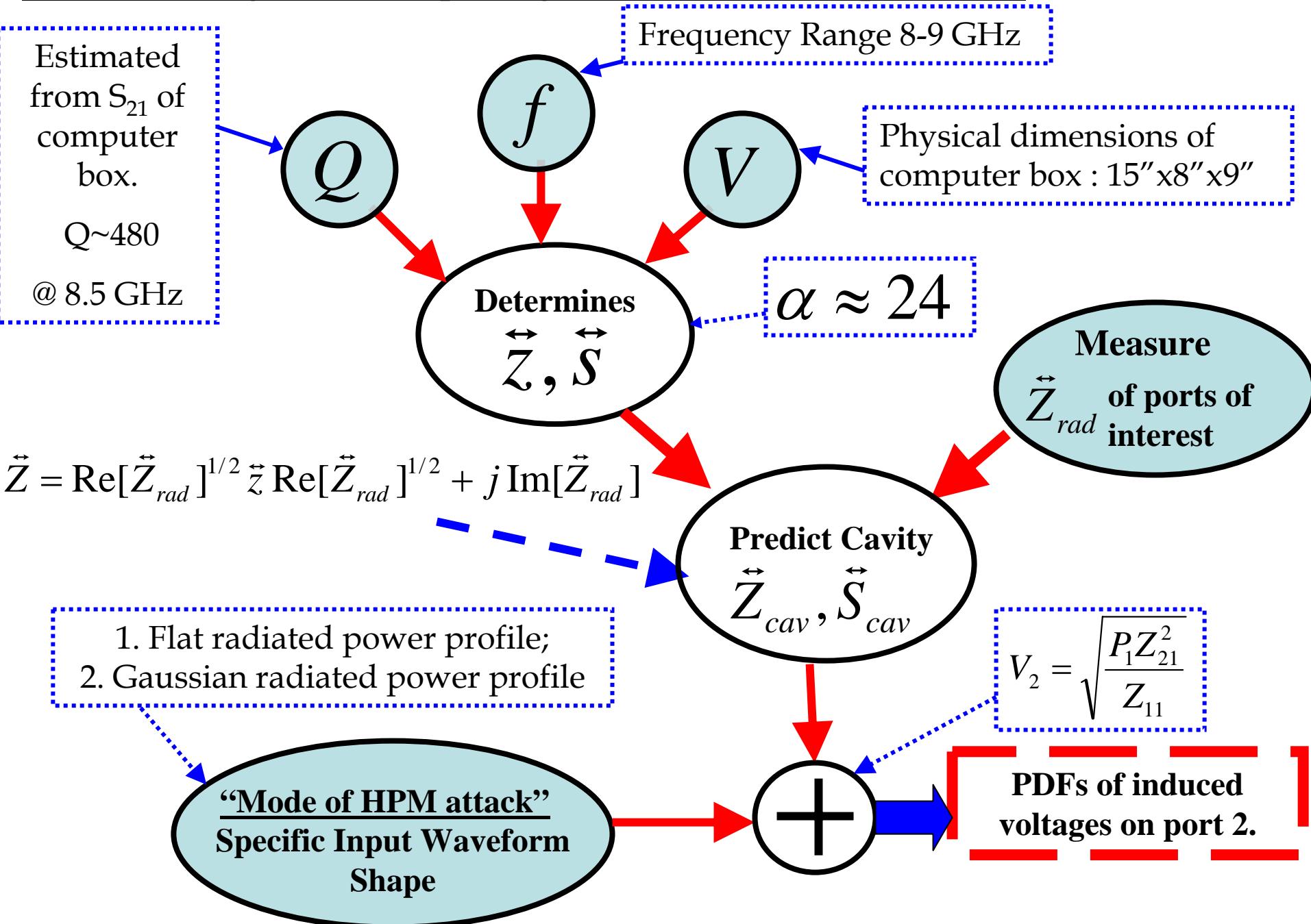


Microwave absorber

Port Radiation Measurement Setup



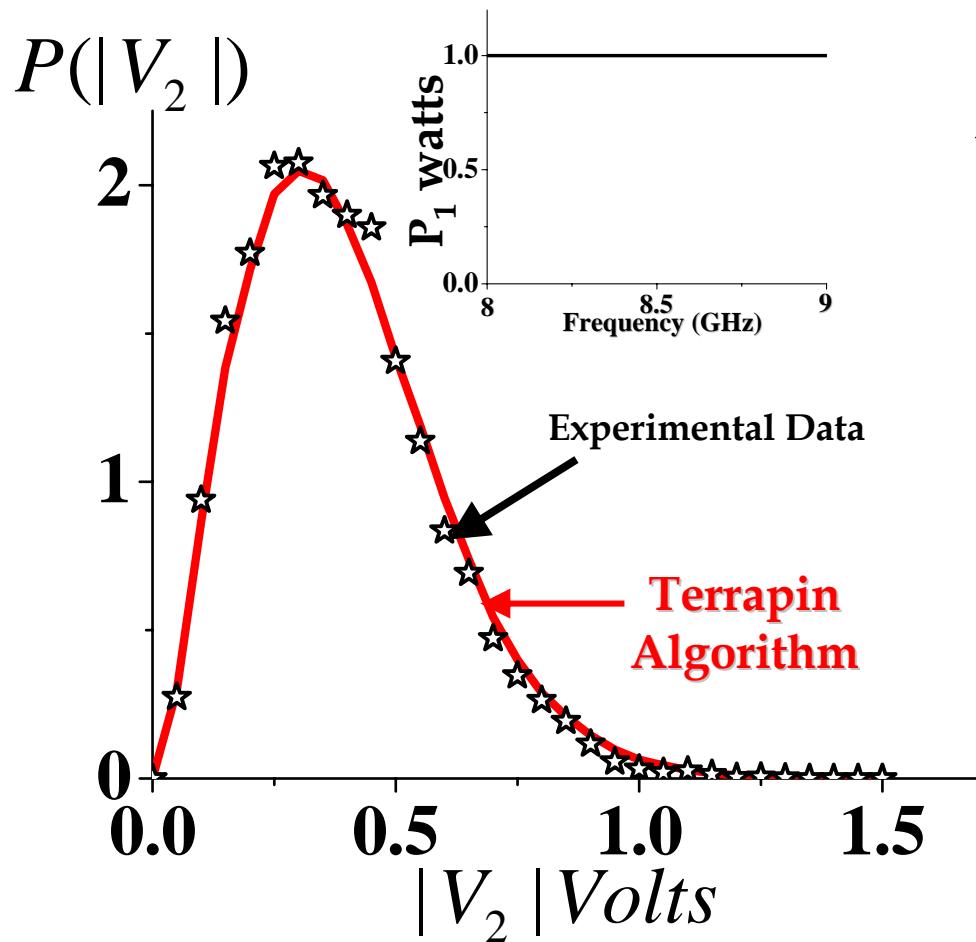
## Tutorial: Using the “Terrapin Algorithm” on the computer-box:



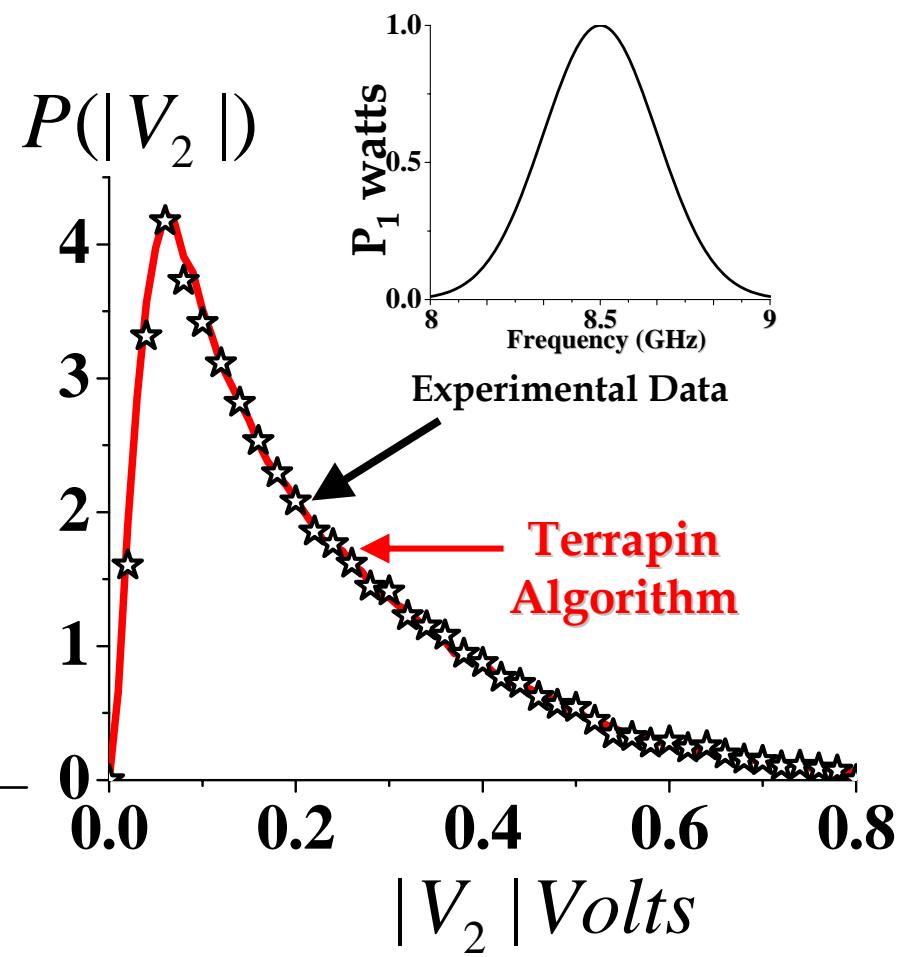
# PDF of induced voltages on port 2 of computer-box

## for different power profiles radiated from Port 1

Flat power-profile  
radiated from port 1

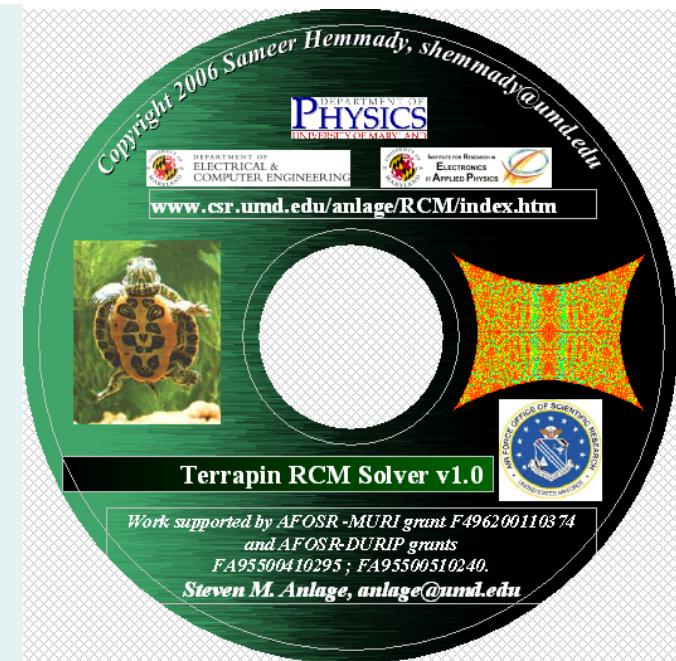


Gaussian-shaped power-profile radiated from port 1

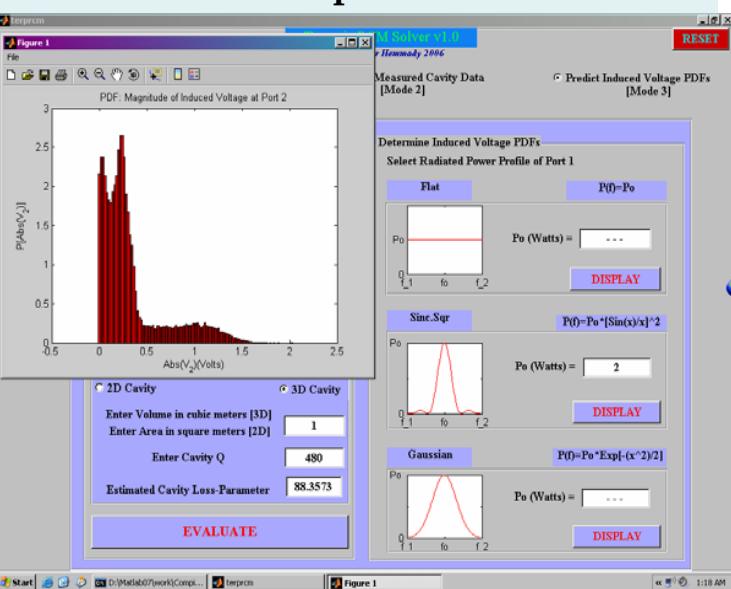


# For the End-User : Terrapin RCM Solver v1.0

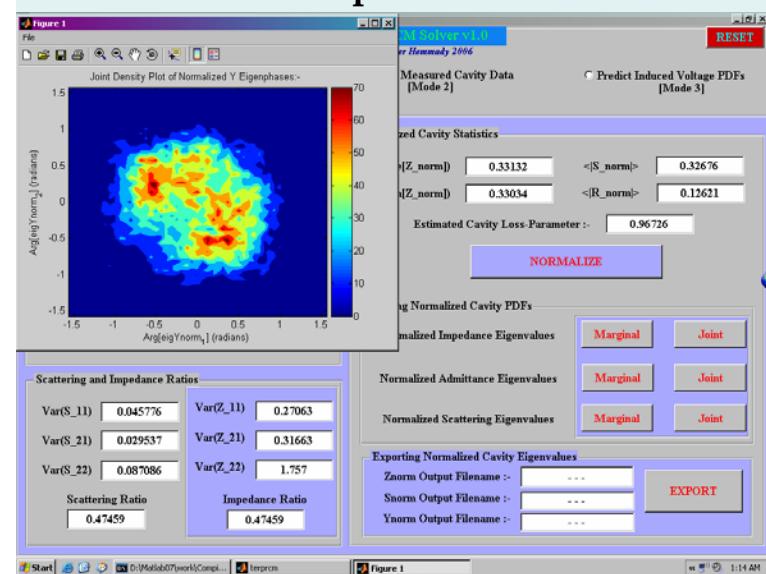
- User-friendly, stand-alone, GUI code using RCM
- Current Capabilities- **Typical run-time ~ 5 to 15 mins**
  - Predict induced voltages in real-world, complicated 2D/3D enclosures with minimum of user-inputs
  - Determine universal fluctuations in user-supplied data on real-world 2D/3D enclosures
  - Generate universal PDFs for user-specified  $\alpha$
  - **www csr umd edu anlage RCM index htm**



## Screenshots- Terrapin RCM Solver v1.0



## Screenshots- Terrapin RCM Solver v1.0



# Conclusions: Extensively validated RCM for 2D/3D cavities. **IT WORKS!!**

- Is there some fast, simple, accurate way to determine *a priori* the voltages induced at specific points within a complicated metallic enclosure (computer-box) due to external radiation?

Use a Statistical Description (RCM).

[www.csr.umd.edu/anlage/RCM/index.htm](http://www.csr.umd.edu/anlage/RCM/index.htm)

- What factors determine the nature of these induced voltages ?

Frequency, Volume of Enclosure, Typical Q of Enclosure,

Radiation Impedance of ports, shape of external radiation wave-form

- Is there some “optimally shaped” waveform for the external radiation, for which the internal electronics is most susceptible ?

See talks by Dr. Steven Anlage ; Dr. John Rodgers to follow.....

“Terrapin Algorithm” : quick insight into induced voltages for given excitation

- Is it possible to engineer an enclosure to make it resistant to HPM attack ?

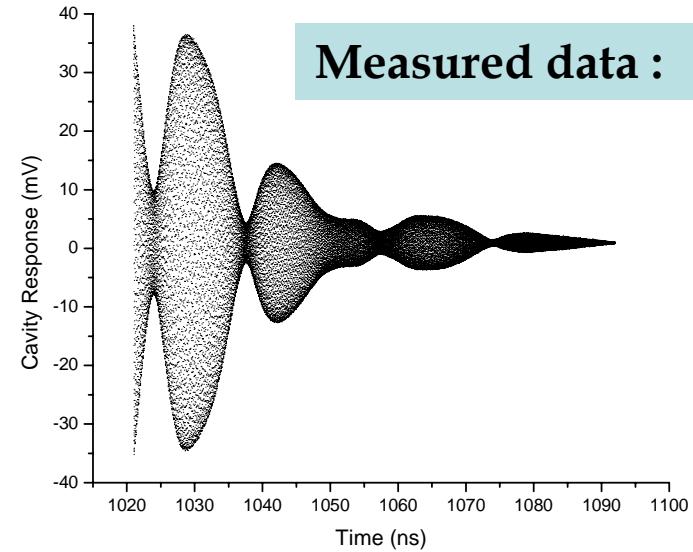
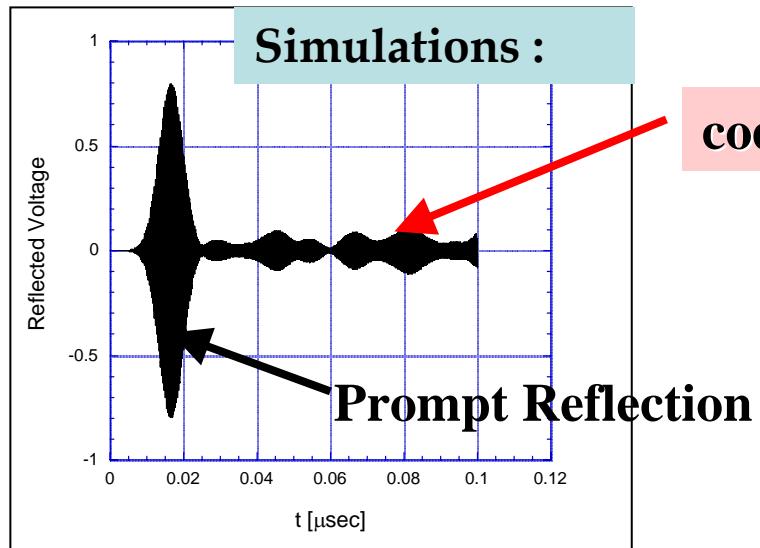
Higher  $\alpha$  =>  
more resistant.

Radiation Impedance  
Engineering

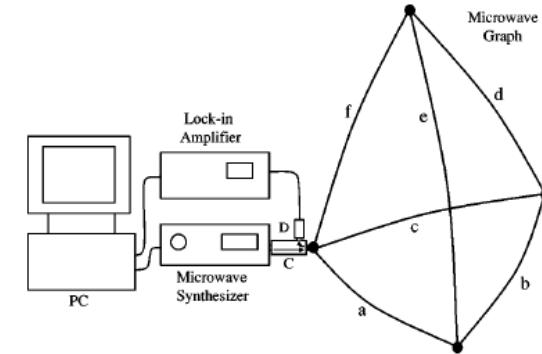
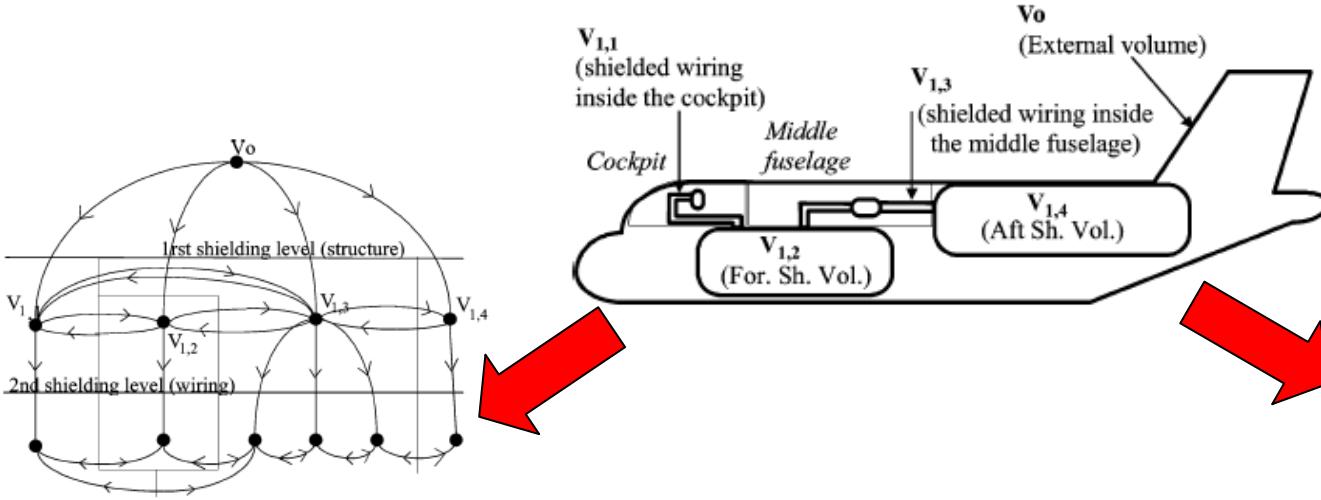
Non-Reciprocal Media  
(Ferrites)

# Future Work:

- Time Domain RCM theory / Experiments: (Hart, Bertrand, Antonsen, Ott, Anlage)



- Quantum Graphs and its applications to EMC topology:



# Publication List: [www.csr.umd.edu/anlage/RCM/index.htm](http://www.csr.umd.edu/anlage/RCM/index.htm)

1. S.Hemmady, *et. al.* “Experimental test of Universal Conductance Fluctuations by means of Wave-Chaotic Microwave Cavities”- **cond-mat/0606650** (submitted to **Phys. Rev. B-RC**).
2. S.Hemmady, *et. al.* “Universal Impedance, Admittance and Scattering Fluctuations of wave-chaotic systems”- **cond-mat/0501231** (submitted to **Phys. Rev. E**).
3. S.Hemmady, *et. al.* “Universal Impedance Fluctuations in Wave-Chaotic Systems” **Phys. Rev. Lett. 94, 014102 (2005)**.
4. S.Hemmady, *et. al.* “Universal Statistics of the Scattering Coefficient of Chaotic Microwave Cavities”- **Phys. Rev. E. 71, 056215 (2005)**.
5. S.Hemmady, *et. al.* “Aspects of the Scattering and Impedance Properties of Chaotic Microwave Cavities”- **Acta Physica Polonica A 109, 65 (2006)**.
6. X. Zheng, *et. al.* “Characterization of Fluctuations of Impedance and Scattering Matrices in Wave-Chaotic Systems”- **Phys. Rev. E. 73, 046208 (2006)**.
7. T.M Antonsen , *et. al.* “Statistical Model for Scattering Matrices of Open Cavities” **URSI EMTS 2004 825-827 (2004)**.

## Random Coupling Model Publications:

1. X. Zheng, T.M.Antonsen, and E. Ott –**Electromagnetics, 26, 3 (2006)**.
2. X. Zheng, T.M.Antonsen, and E. Ott –**Electromagnetics, 26, 37 (2006)**.

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